

DIN EN 16602-60-13:2023-10 (E)

Space product assurance - Commercial, electrical, electronic and electromechanical (EEE) components; English version EN 16602-60-13:2023

Table of contents

European Foreword	5
Introduction	6
1 Scope	8
2 Normative references	9
3 Terms, definitions and abbreviated terms	11
3.1 Terms from other standards.....	11
3.2 Terms specific to the present standard	11
3.3 Abbreviated terms.....	12
3.4 Conventions.....	13
3.5 Nomenclature	14
3.6 Convention for the Applicability Matrix	15
4 Requirements for class 1 components	16
5 Requirements for class 2 components	28
6 Requirements for class 3 components	39
7 Quality levels	50
8 Evaluation, screening and LAT tests	51
9 Pure tin lead finish – risk analysis	93
Annex A (normative) Component control plan (CCP) - DRD	94
Annex B (normative) Declared components list (DCL) - DRD	95
Annex C (normative) Internal Supplier’s specification - DRD	96
Annex D (normative) Parts approval document - DRD	97
Annex E (informative) EEE documents delivery per review	98
Annex F (normative) Justification document - DRD	99
Annex G <<deleted>>	102

Annex H (informative) Flow chart for construction analysis	103
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Bibliography.....	106
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Figures

Figure 4-1: <<deleted>>	20
Figure 4-2: <<deleted>>	23
Figure 5-1: <<deleted>>	32
Figure 5-2: <<deleted>>	35
Figure 6-1: <<deleted>>	45
Figure 8-1: <<deleted>>	51
Figure 8-2: <<deleted>>	51
Figure 8-3: <<deleted>>	51
Figure 8-4: <<deleted>>	51
Figure 8-5: <<deleted>>	51
Figure 8-6: <<deleted>>	51

Tables

Table 4-1: <<deleted and moved as legacy test files as Table 8-9>>	20
Table 4-2: <<deleted and moved as legacy test files as Table 8-10>>	23
Table 4-3: <<deleted and moved as legacy test files as Table 8-11>>	23
Table 4-4: Documentation for Class 1 components	27
Table 5-1: <<deleted and moved as Legacy test files as Table 8-12>>	32
Table 5-2: <<deleted and moved as Legacy test files as Table 8-13>>	34
Table 5-3: <<deleted and moved to Legacy test files as Table 8-14>>	35
Table 5-4: Documentation for Class 2 components	38
Table 6-1: <<deleted>>	42
Table 6-2: <<deleted>>	44
Table 6-3: <<deleted and moved as Legacy test files Table 8-15>>	45
Table 6-4: Documentation for Class 3 components	48
Table 8-1: Procurement test table for ceramic capacitors chips	54
Table 8-2: Procurement test table for solid electrolyte tantalum capacitors chips.....	56
Table 8-3: Procurement test table for discrete parts (diodes, transistors, optocouplers)	58
Table 8-4: Procurement test table for fuses	60
Table 8-5: Procurement test table for magnetics.....	63
Table 8-6: Procurement test table for microcircuits	66
Table 8-7: Procurement test table for resistor chips	68

Table 8–8: Procurement test table for Thermistors	71
Table 8–9: Legacy test files - Evaluation tests for Class 1 components - Active parts ..	74
Table 8–10: Legacy test files - Screening tests for Class 1 components - Active parts	77
Table 8–11: Legacy test files - Lot acceptance tests for Class 1 components - Active parts.....	79
Table 8–12: Legacy test files - Evaluation tests - Class 2 components - Active parts ..	82
Table 8–13: Legacy test files - Screening tests - Class 2 components - Active parts...	85
Table 8–14: Legacy test files - Lot acceptance tests - Class 2 components – Active parts	87
Table 8–15: Legacy test files - LAT tests - Class 3 components - Active parts	90
Table H-1 : <<deleted>>	103
Table H-2 : Construction analysis sequence.....	104